

Specifications



SY	ST	EM		

6314-0100-01 ZYGO P/N

Manual 100x50 mm XY Motion Kit Configuration Motorized 100x100 mm XY Motion Kit

Options Extended work volume head mounting

Non-contact, three-dimensional, coherence

Measurement Technique scanning interferometry

> Scanner Long range z-stage

1X - 50X magnification; Objectives

Standard and long working distance

Objective Mounting Options

• Single objective dovetail (standard)

· Manual or motorized 4 obj. turret (option)

Objective dependent

Field of View See the Nexview NX2 / NewView 9000 /

ZeGage Pro Objective Chart for details

Integrated long-life white light LED with Illuminator

computer controlled light level

Measurement Selectable 1600 x 1200, 1000 x 1000,

1000 x 600, 1000 x 200 Array

Part Viewing Integrated view window in Mx software

Mx powered Part Finder with Fast Focus Focus Assist

Technology

100 mm travel; head may be mounted at 7-Drive either of 2 heights for optimal work volume (Focus) Stage

> Manual Tip/Tilt Stage with ±4° travel, and integrated t-slot fixture plate (standard on

all configurations)

Part Stage • Manual XY w 50 x 100 mm

x/y travel

• Motorized X/Y w/ 100 x 100 mm

x/y travel

ZYGO XYZ pendant with joystick, speed Stage Control

control, z-stop and emergency stop

System Controller

Dimensions

i7 class PC with 23 in. 1080P display

ZYGO Mx software running under Microsoft Software

Windows 7 (64-bit)

PHYSICAL

156 x 127 x 76 cm

(ZeGage on workstation table)

(HWD) 82 x 53 x 53 cm (ZeGage)

74 x 127 x 76 cm (Workstation Table)

Weight

ZeGage: 54 kg

Workstation Table: 37 kg

UTILITY REQUIREMENTS

Input Voltage 100 to 240 VAC, 50/60 Hz **PERFORMANCE**

≤ 20 mm

Vertical Scan Range

(limited by objective working

distance) ≤ 3.5 nm

Surface Topography

Repeatability(1)

0.1 nm

Repeatability of RMS⁽²⁾

Optical Lateral

0.52 µm (50X objective) Resolution(3)

Spatial Sampling

0.17 µm (50X objective) 32 µm/sec @ 1600 x 1200

Data Scan Speed⁽⁴⁾

42 µm/sec @ 1000 x 1000 64 µm/sec @ 1000 x 600 171 µm/sec @ 1000 x 200

Step Height

Repeatability(5)

 $\leq 0.3\% \ @1\sigma$

Step Height Accuracy ≤ 3%

TEST PART CHARACTERISTICS

Opaque, transparent, coated, Material

uncoated, specular, rough

87 x 100 x 100 mm for 100 mm

XY coverage using std. head pos.

147 x 100 x 100 mm for 100 mm Maximum Size (HWD) XY coverage using ext. head pos.

Larger sample width and depth

possible with partial coverage

Sample Reflectivity 0.05% - 100%

ENVIRONMENTAL REQUIREMENTS

Temperature

15 to 30°C with rate of change

<1.0°C per 15 min

Humidity

5 to 95% relative, noncondensing

Vibration Isolation

No external isolation required

Vibration Criterion

VC-A or better (recommended)

FOOTNOTES

Performance specifications under laboratory conditions using standard specimens, according to ISO 25178-601, 25178-604 and 5436-1.

- Single measurements at 7.8 μ m/sec scan speed, 1 million image points, 3×3 pixel denoising filter.
- Repeatability of the RMS surface roughness parameter Sq, under the same conditions as for (1). Note that the repeatability of the Sq is sometimes referred to informally as "vertical resolution."
- (3) Lateral Resolution=sparrow criterion, objective dependent.
- Data scan speed depends on the measurement array and data acquisition mode.
- 1- σ Step height repeatability verified using 1.8 μ m and 24 μ m NIST-traceable step height standards.

Specifications subject to change without prior notice.

